


<p><i>Search Notes</i></p> 	<p>Application/Control No.</p> <p>10067658</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>BEAN ET AL.</p>
	<p>Examiner</p> <p>KELLY L JERABEK</p>	<p>Art Unit</p> <p>2622</p>

SEARCHED			
Class	Subclass	Date	Examiner
348	229.1, 296, 312-322, 362	2/23/2009	KJ
		2/24/2009	

SEARCH NOTES		
Search Notes	Date	Examiner
NPL Search	2/23/2009	KJ
EAST Keyword		
EIC 2600 STIC PLUS Search	2/24/2009	

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	PGPub Text Search - See Attached Sheet	2/24/2009	KJ

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